Hybrid 8j206 Traveler

April 28, 2000

1 Connectivity

Repairs on shorts:
Fixes for opens:

2 Chips

The following chips were assembled on this hybrid (in the order that the chips get read out):
Hybrid 8J206 has die: 177-108 177-110 177-111 177-112 179-100 179-102 179-103 179-104

3 Data Analysis Summary

The following summarizes the findings of the Burn-in data analysis program. The first chip in the readout name is numbered 0.

```
% Hybrid 8j206 classification info. Created 09:24:15 04/28/00

Hybrid 8j206 quality: fair
Chip classification: good good good good good good good fair
Bad channels: none
Bad cells: none
Random bad capacitors (chip-cell-channel): 7-10-75 7-10-76 7-13-75
   7-13-76 7-15-75 7-15-76 7-17-75 7-17-76 7-26-74 7-26-75 7-26-76
   7-26-77 7-27-75 7-27-76 7-39-75 7-39-76 7-6-76
Channels at pedestal needed for DCMS: 33.7 33.6 31.6 34.6 29.7 32.6 34.7 35.6
```

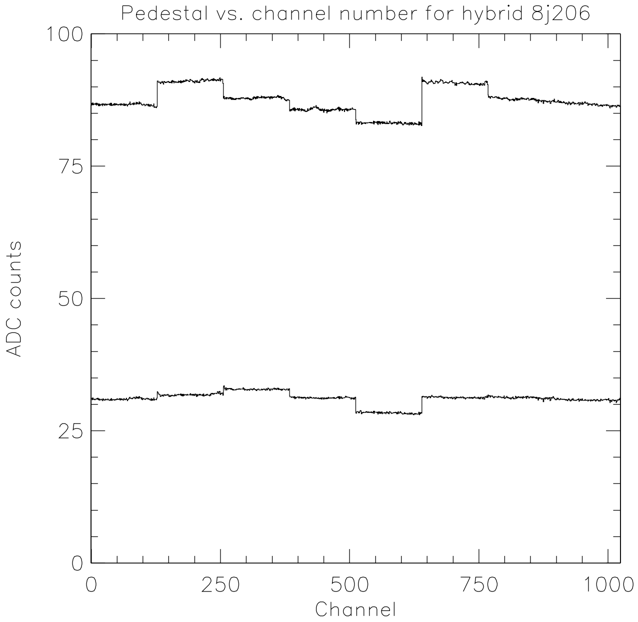
4 Comments

HV tested.

5 Pedestal

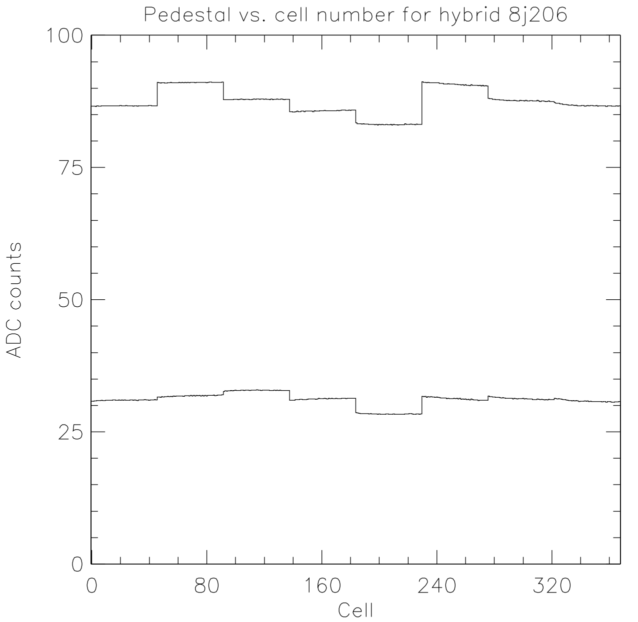
The following plot shows the pedestals vs. channel number with and without charge injection:

Pedestal for each Channel



The following plot shows the average pedestal vs. pipeline cell ID with and without charge injection. The x-axis is cell ID offset by 46 for each chip. Thus cell ID 5 for chip 1 is at x=5, chip 2 at x=51, chip 3 at x=97, etc.

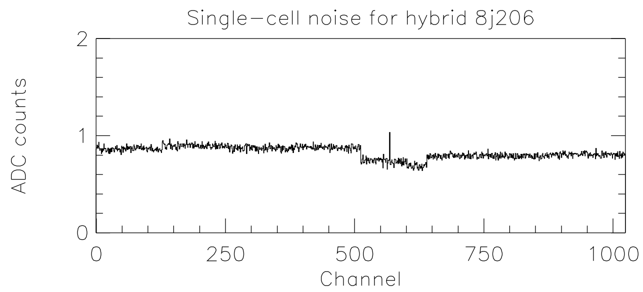
Pedestal vs. Pipeline Cell ID

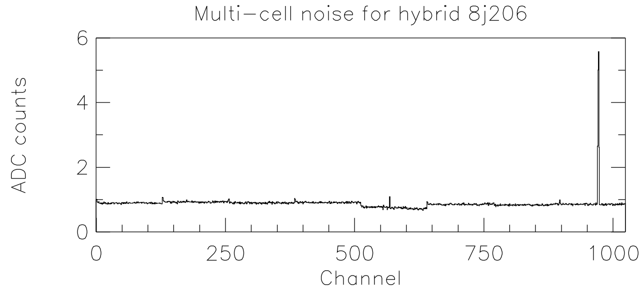


6 Noise

The following plots show the single-cell and multi-cell RMS noise:

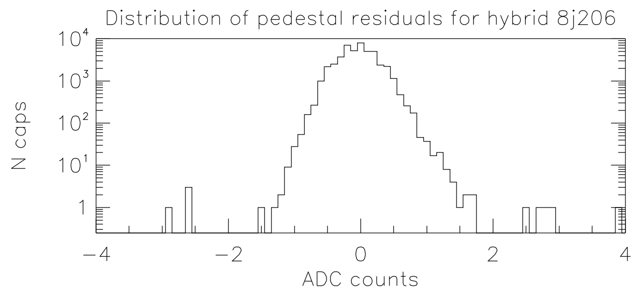
RMS Noise

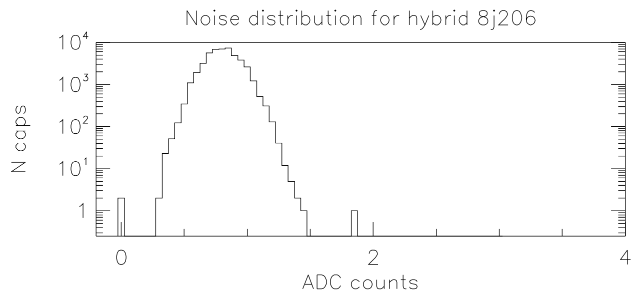




The following are histograms of the pedestal of each pipeline capacitor relative to the chip average (top); and the RMS noise of each capacitor (bottom):

Distribution of Pedestals and Noise





7 Currents

The following plots show the supply currents per chip as a function of measurment number. Currents are measured approximately every 10 minutes:

Supply Currents During Burn-in